

Date: 2025-06-12

System Check_Head_2450MHz**DUT: D2450V2 - SN1095**

Communication System: CW; Frequency: 2450.000 MHz; Duty Cycle: 1:1

Medium: HSL_2450_250612 Medium parameters used: $f = 2450.000$ MHz; $\sigma = 1.77$ S/m; $\epsilon_r = 39.3$

Ambient Temperature: 23.2°C; Liquid Temperature: 22.8°C

DASY6 Configuration:

- Probe: EX3DV4 - SN7630; ConvF(7.32, 7.48, 7.18); Calibrated: 2024-08-22
- Sensor-Surface: 1.4 mm
- Electronics: DAE4 Sn1650; Calibrated: 2024-11-25
- Phantom: ELI V8.0 (20deg probe tilt); Serial: 2074; Section: Flat
- Measurement Software: 16.4.0.5005
- UID: CW, 0--

Pin=50mW/Area Scan (40.0 mm x 80.0 mm): Measurement Grid: 10.0 mm x 10.0 mm

SAR (1g) = 2.69 W/kg; SAR (10g) = 1.19 W/kg;

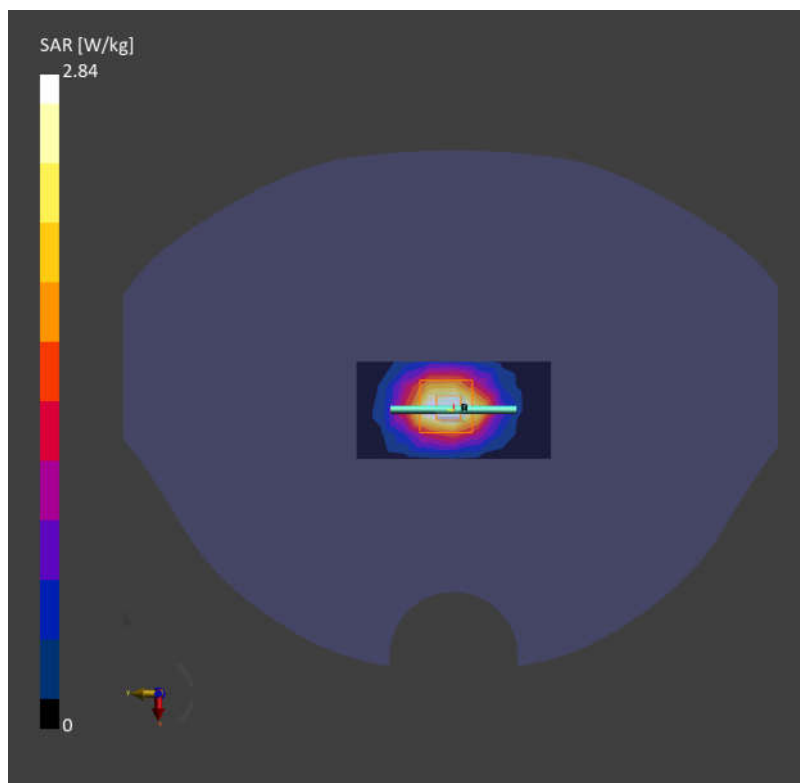
Pin=50mW/Zoom Scan (30.0 mm x 30.0 mm x 30.0 mm): Measurement Grid: 5.0 mm x 5.0 mm x 1.5 mm

Power Drift = -0.02 dB

SAR (1g) = 2.84 W/kg; SAR (10g) = 1.29 W/kg

Smallest distance from peaks to all points 3 dB below = 9.5 mm

Ratio of SAR at M2 to SAR at M1 = 83.3 %



Date: 2025-06-14

System Check_Head_5250MHz**DUT: D5GHzV2 - SN1113**

Communication System: CW; Frequency: 5250.000 MHz; Duty Cycle: 1:1

Medium: HSL_5250_250614 Medium parameters used: $f = 5250.000$ MHz; $\sigma = 4.67$ S/m; $\epsilon_r = 36.3$

Ambient Temperature: 23.1°C; Liquid Temperature: 22.7°C

DASY6 Configuration:

- Probe: EX3DV4 - SN7630; ConvF(6.05, 6.18, 5.93); Calibrated: 2024-08-22
- Sensor-Surface: 1.4 mm
- Electronics: DAE4 Sn1650; Calibrated: 2024-11-25
- Phantom: ELI V8.0 (20deg probe tilt); Serial: 2074; Section: Flat
- Measurement Software: 16.4.0.5005
- UID: CW, 0--

Pin=50mW/Area Scan (40.0 mm x 80.0 mm): Measurement Grid: 10.0 mm x 10.0 mm

SAR (1g) = 3.48 W/kg; SAR (10g) = 1.05 W/kg;

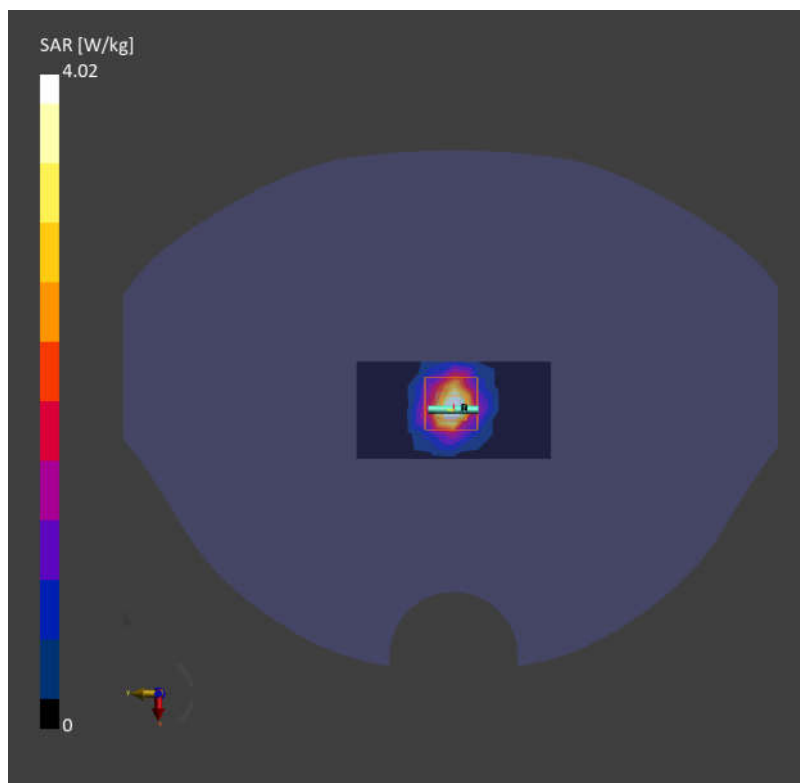
Pin=50mW/Zoom Scan (22.0 mm x 22.0 mm x 22.0 mm): Measurement Grid: 4.0 mm x 4.0 mm x 1.4 mm

Power Drift = -0.00 dB

SAR (1g) = 4.02 W/kg; SAR (10g) = 1.20 W/kg

Smallest distance from peaks to all points 3 dB below = 7.2 mm

Ratio of SAR at M2 to SAR at M1 = 64.8 %



Date: 2025-06-15

System Check_Head_5600MHz**DUT: D5GHzV2 - SN1113**

Communication System: CW; Frequency: 5600.000 MHz; Duty Cycle: 1:1

Medium: HSL_5600_250615 Medium parameters used: $f = 5600.000$ MHz; $\sigma = 5.00$ S/m; $\epsilon_r = 35.8$

Ambient Temperature: 23.1°C; Liquid Temperature: 22.8°C

DASY6 Configuration:

- Probe: EX3DV4 - SN7630; ConvF(5.4, 5.52, 5.3); Calibrated: 2024-08-22
- Sensor-Surface: 1.4 mm
- Electronics: DAE4 Sn1650; Calibrated: 2024-11-25
- Phantom: ELI V8.0 (20deg probe tilt); Serial: 2074; Section: Flat
- Measurement Software: 16.4.0.5005
- UID: CW, 0--

Pin=50mW/Area Scan (40.0 mm x 80.0 mm): Measurement Grid: 10.0 mm x 10.0 mm

SAR (1g) = 3.74 W/kg; SAR (10g) = 1.12 W/kg;

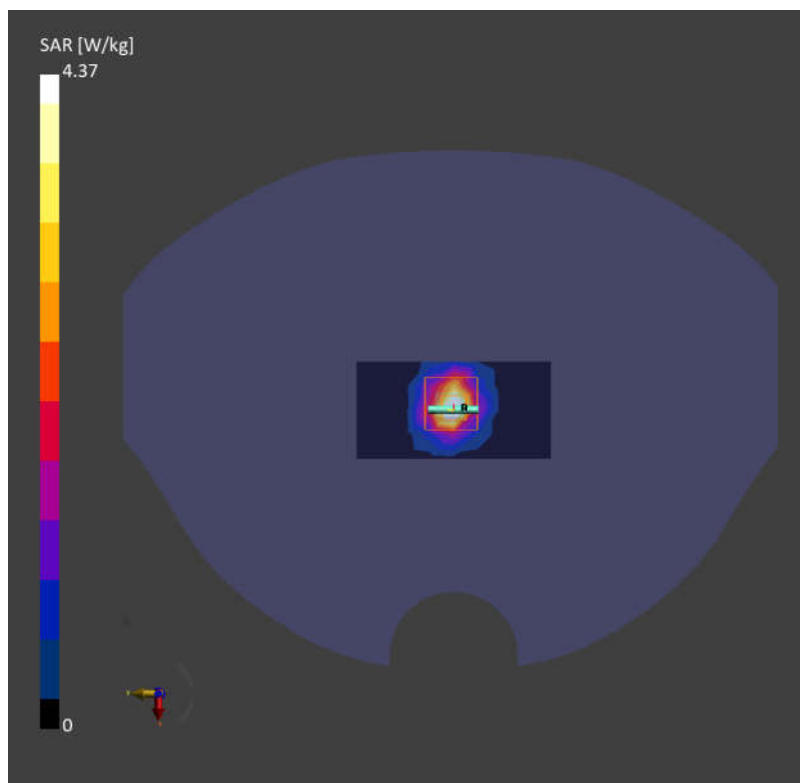
Pin=50mW/Zoom Scan (22.0 mm x 22.0 mm x 22.0 mm): Measurement Grid: 4.0 mm x 4.0 mm x 1.4 mm

Power Drift = 0.02 dB

SAR (1g) = 4.37 W/kg; SAR (10g) = 1.28 W/kg

Smallest distance from peaks to all points 3 dB below = 7.4 mm

Ratio of SAR at M2 to SAR at M1 = 61.9 %



Date: 2025-06-16

System Check_Head_5750MHz**DUT: D5GHzV2 - SN1113**

Communication System: CW; Frequency: 5750.000 MHz; Duty Cycle: 1:1

Medium: HSL_5750_250616 Medium parameters used: $f = 5750.000$ MHz; $\sigma = 5.17$ S/m; $\epsilon_r = 35.6$

Ambient Temperature: 23.2°C; Liquid Temperature: 22.6°C

DASY6 Configuration:

- Probe: EX3DV4 - SN7630; ConvF(5.55, 5.67, 5.44); Calibrated: 2024-08-22
- Sensor-Surface: 1.4 mm
- Electronics: DAE4 Sn1650; Calibrated: 2024-11-25
- Phantom: ELI V8.0 (20deg probe tilt); Serial: 2074; Section: Flat
- Measurement Software: 16.4.0.5005
- UID: CW, 0--

Pin=50mW/Area Scan (40.0 mm x 80.0 mm): Measurement Grid: 10.0 mm x 10.0 mm

SAR (1g) = 3.39 W/kg; SAR (10g) = 1.02 W/kg;

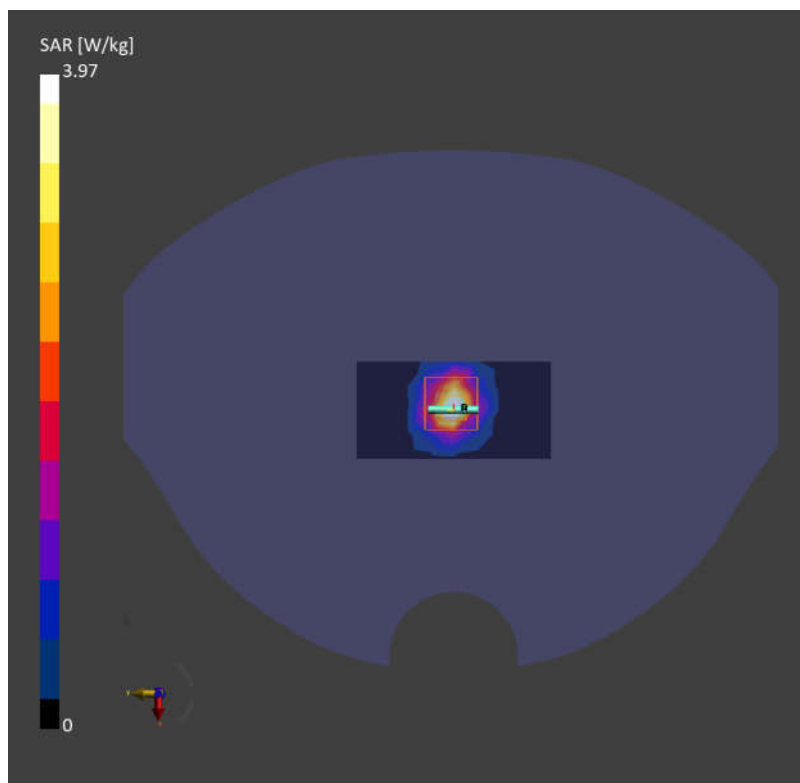
Pin=50mW/Zoom Scan (22.0 mm x 22.0 mm x 22.0 mm): Measurement Grid: 4.0 mm x 4.0 mm
mm x 1.4 mm

Power Drift = 0.03 dB

SAR (1g) = 3.97 W/kg; SAR (10g) = 1.17 W/kg

Smallest distance from peaks to all points 3 dB below = 7.6 mm

Ratio of SAR at M2 to SAR at M1 = 59.8 %



System Check_Head_2450MHz-C-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

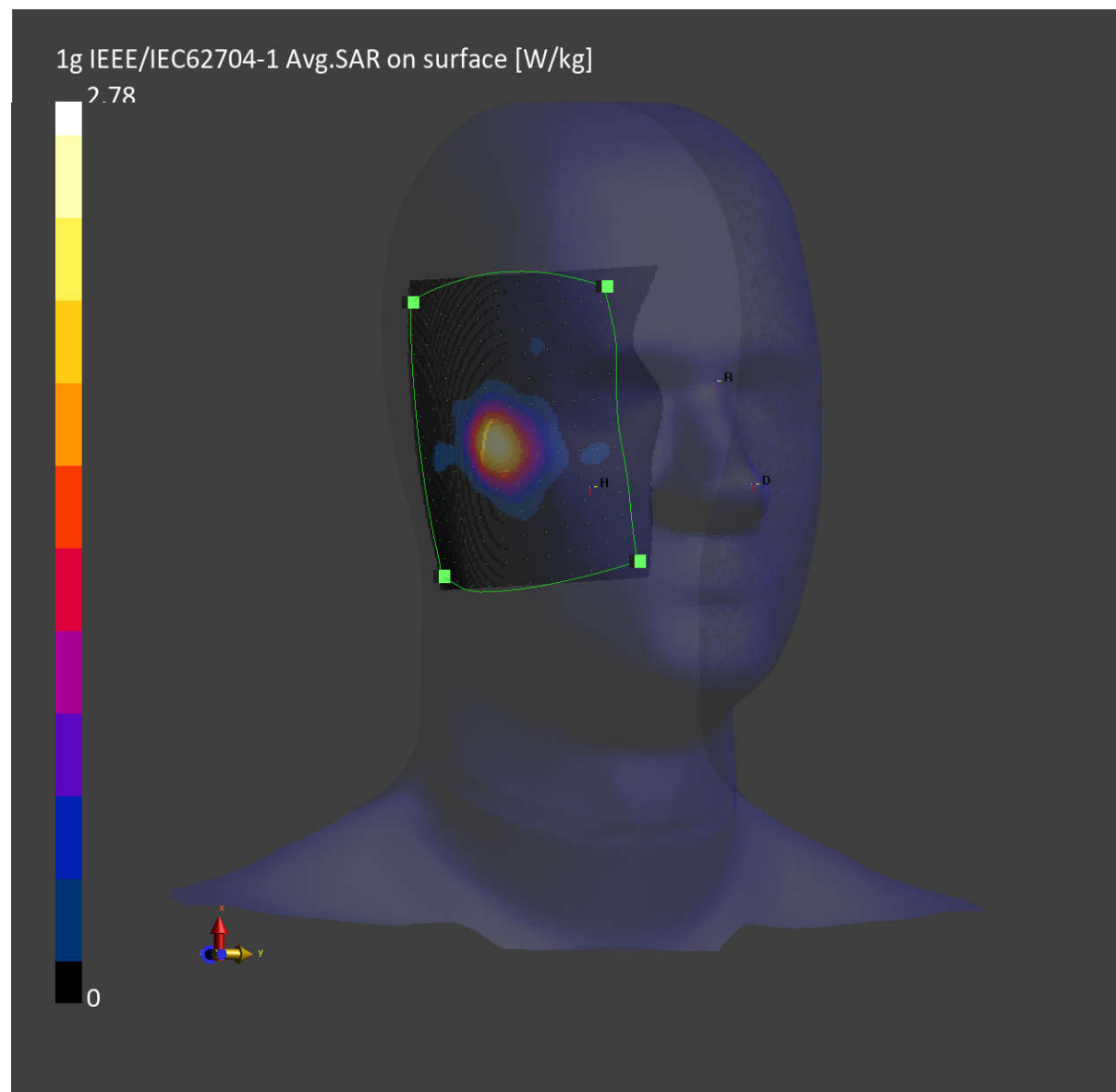
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	120.0 x 110.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.55	2.78
psSAR10g [W/Kg]	1.13	1.33
Power Drift [dB]	0.03	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		9.8

SAR Pattern



System Check_Head_2450MHz-F-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

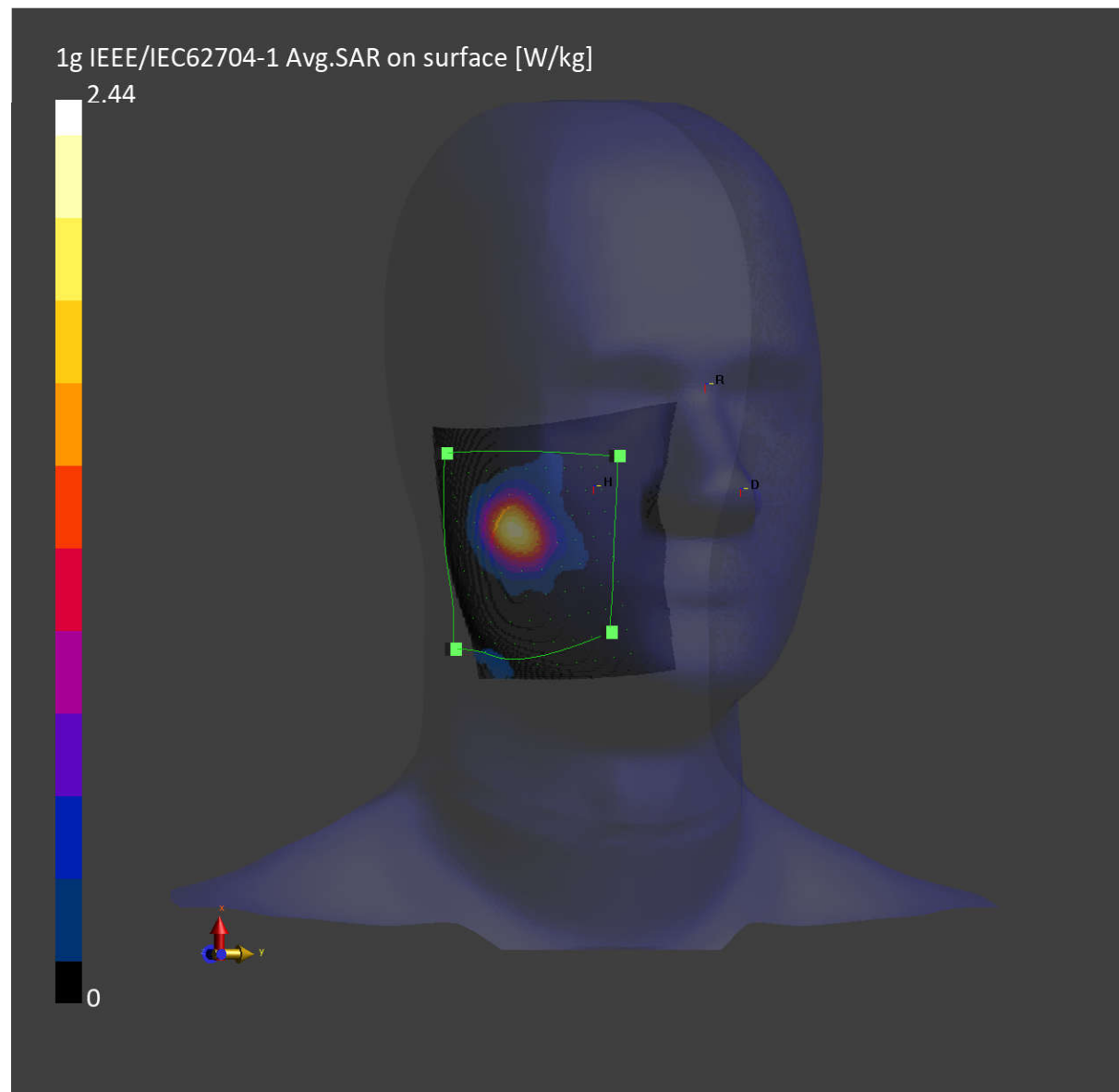
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	100.0 x 100.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.14	2.44
psSAR10g [W/Kg]	0.983	1.19
Power Drift [dB]	0.63	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		10.0

SAR Pattern



System Check_Head_2450MHz-H-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

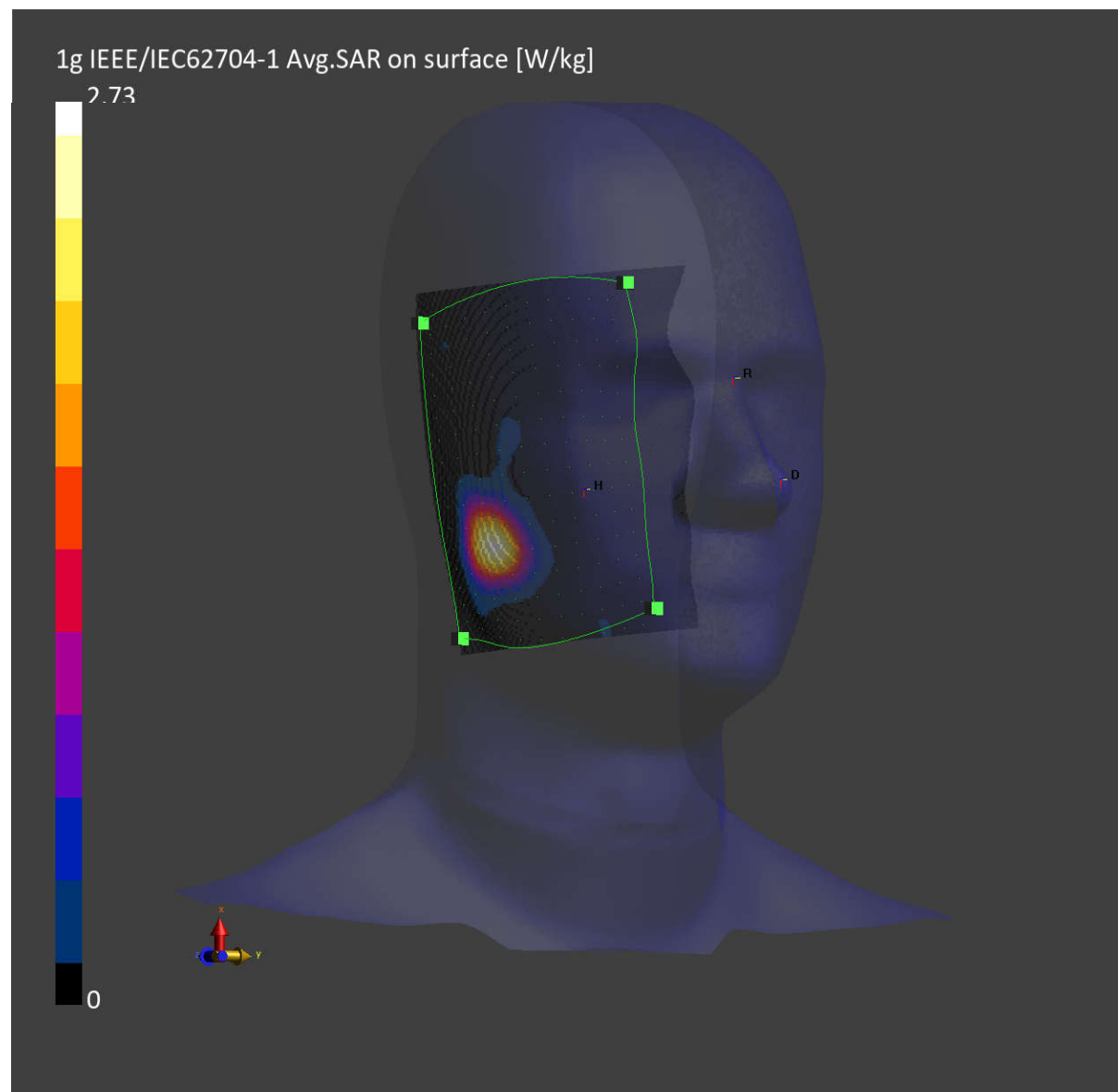
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	140.0 x 110.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.58	2.73
psSAR10g [W/Kg]	1.23	1.32
Power Drift [dB]	N/A	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.6
Dist 3dB Peak [mm]		9.1

SAR Pattern



System Check_Head_2450MHz-C-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

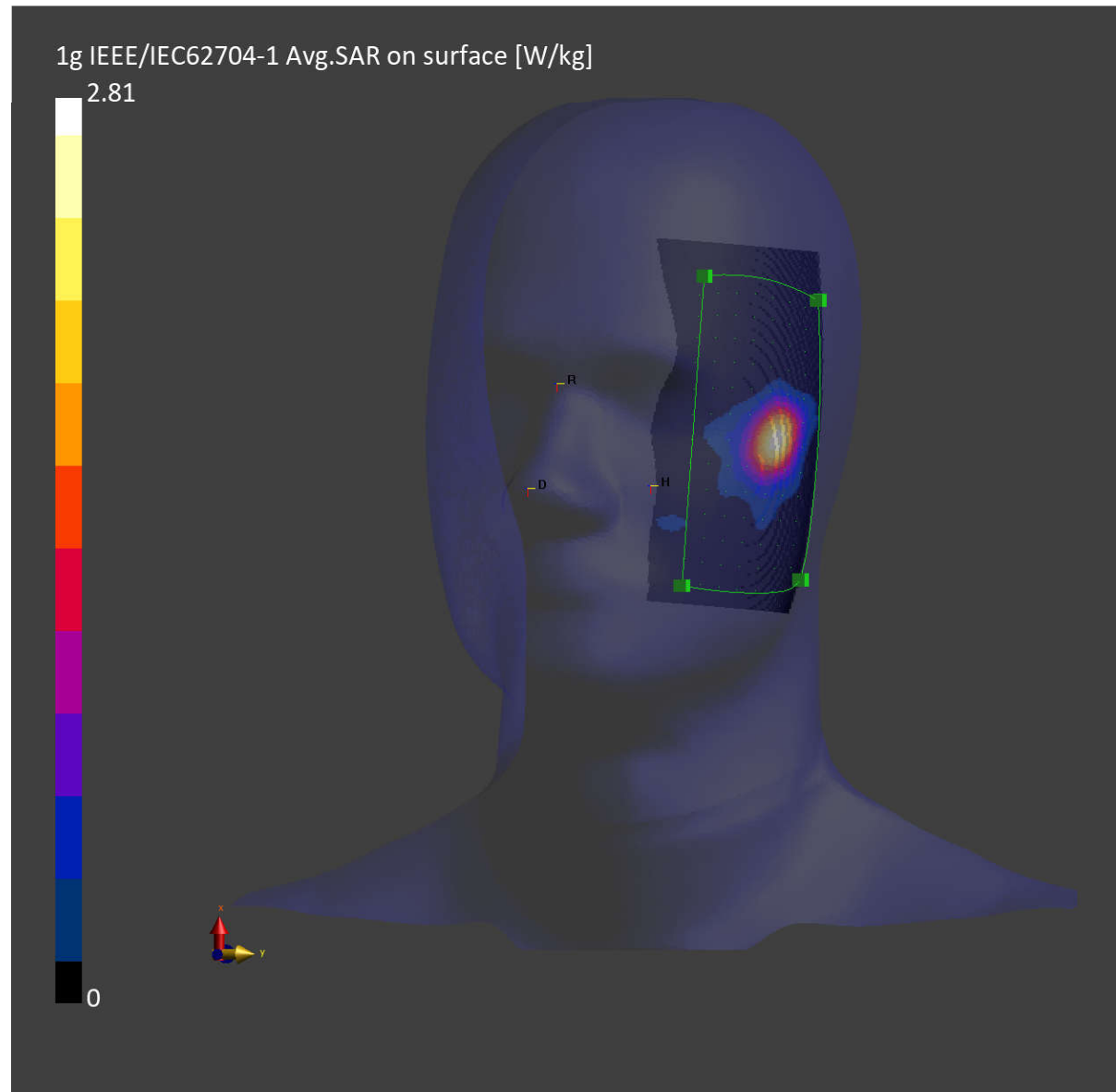
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	140.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.50	2.81
psSAR10g [W/Kg]	1.13	1.33
Power Drift [dB]	0.19	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.0
Dist 3dB Peak [mm]		9.2

SAR Pattern



System Check_Head_2450MHz-F-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

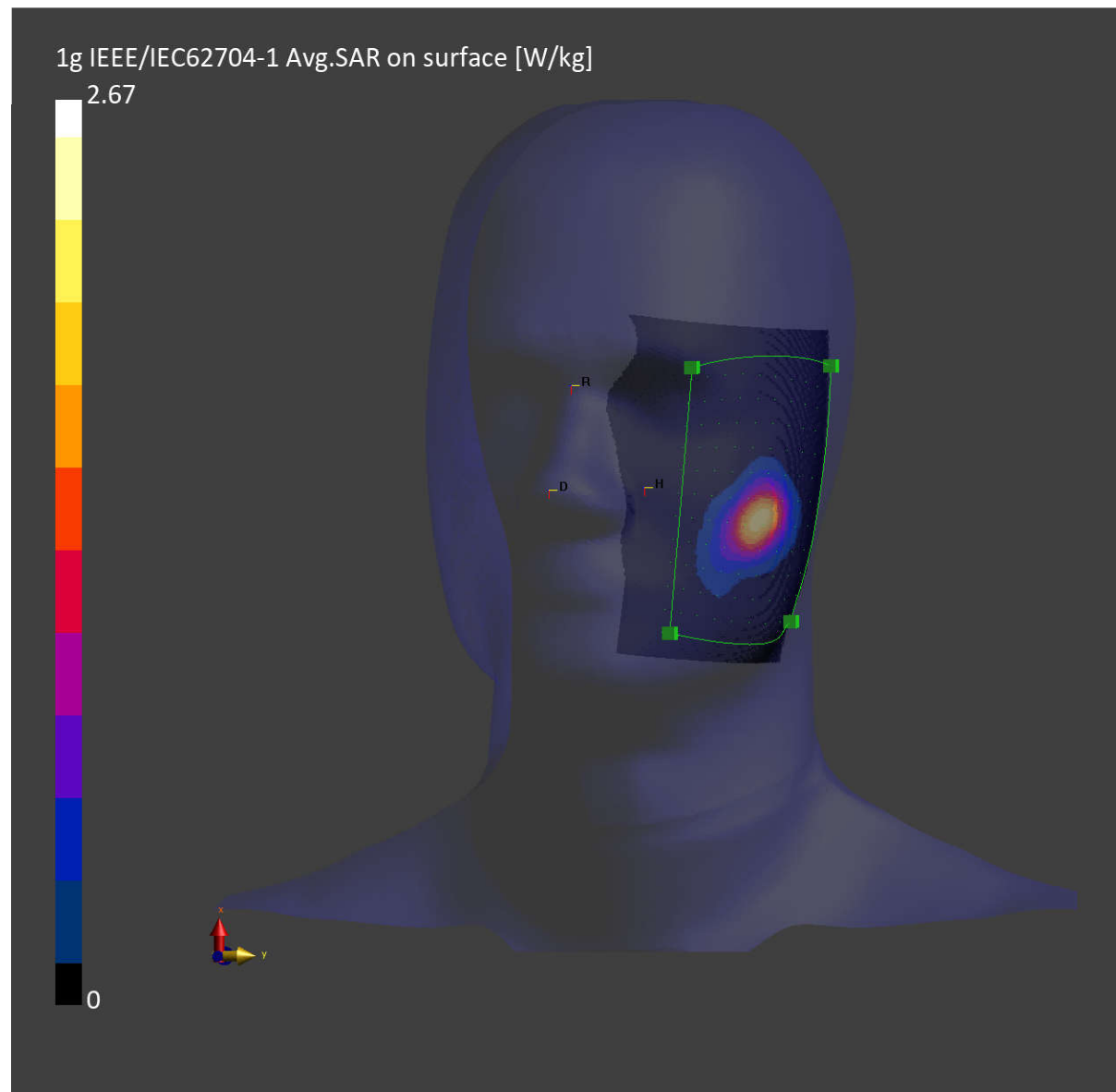
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	130.0 x 100.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.16	2.67
psSAR10g [W/Kg]	1.00	1.28
Power Drift [dB]	0.15	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.9
Dist 3dB Peak [mm]		9.8

SAR Pattern



System Check_Head_2450MHz-H-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D2450	CW, 0--	2450.000, 50	7.32	1.77	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_2450_250612	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

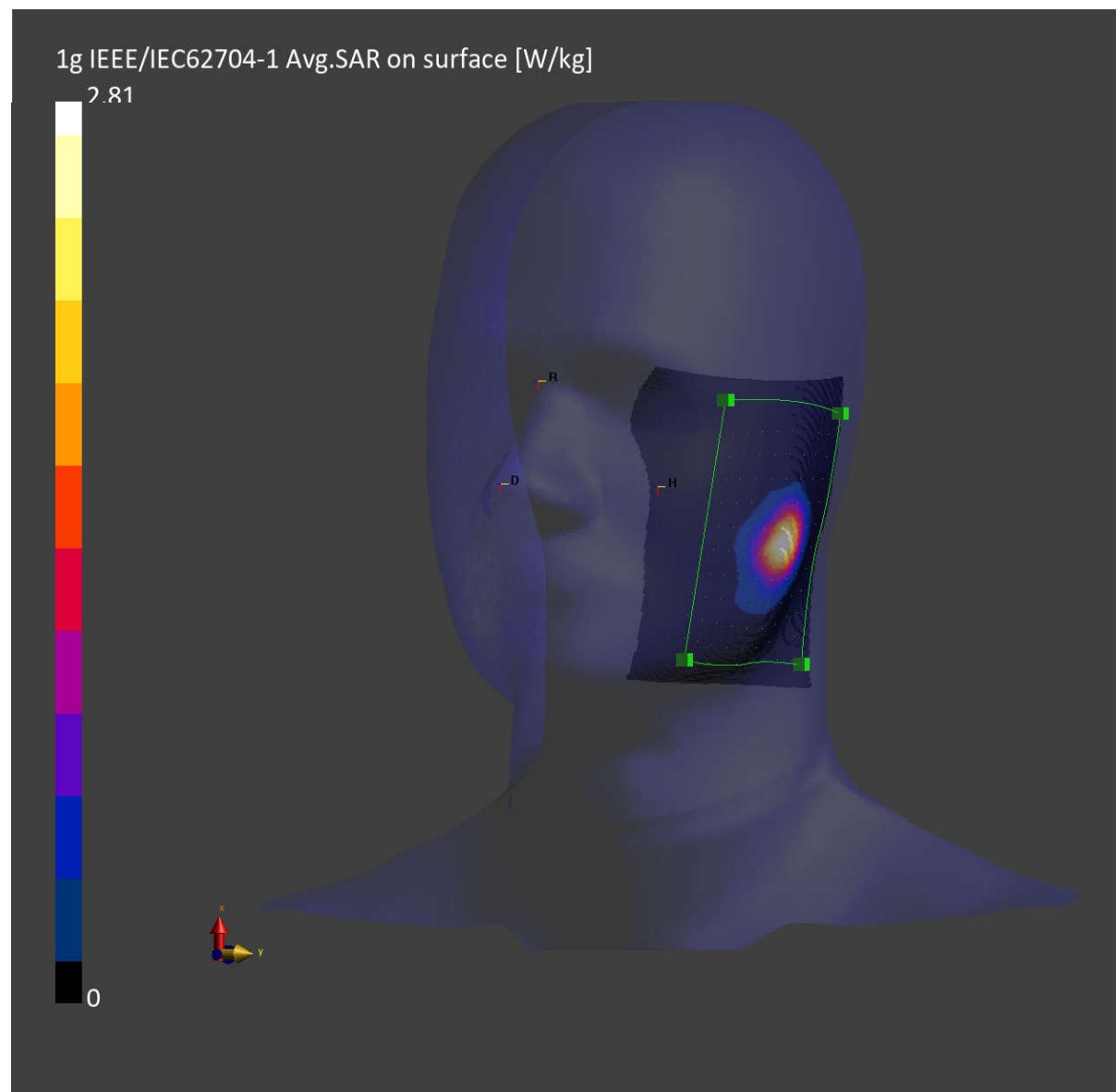
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	120.0 x 100.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-12	2025-06-12
psSAR1g [W/Kg]	2.59	2.81
psSAR10g [W/Kg]	1.15	1.34
Power Drift [dB]	-0.95	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		9.4

SAR Pattern



System Check_Head_5800MHz-C-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

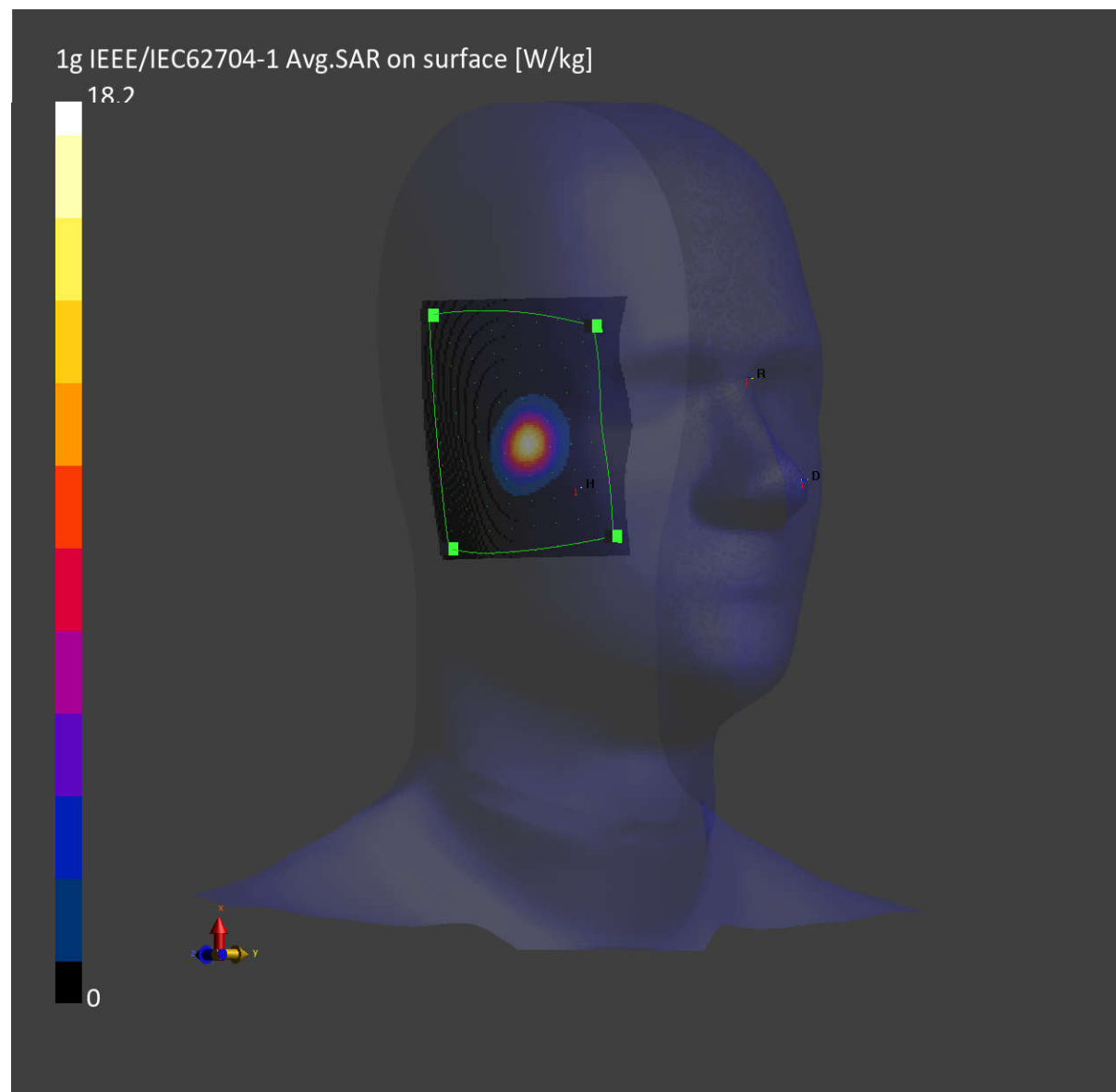
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	100.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	17.0	18.2
psSAR10g [W/Kg]	4.75	4.93
Power Drift [dB]	-0.90	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.8
Dist 3dB Peak [mm]		4.8

SAR Pattern



System Check_Head_5800MHz-F-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

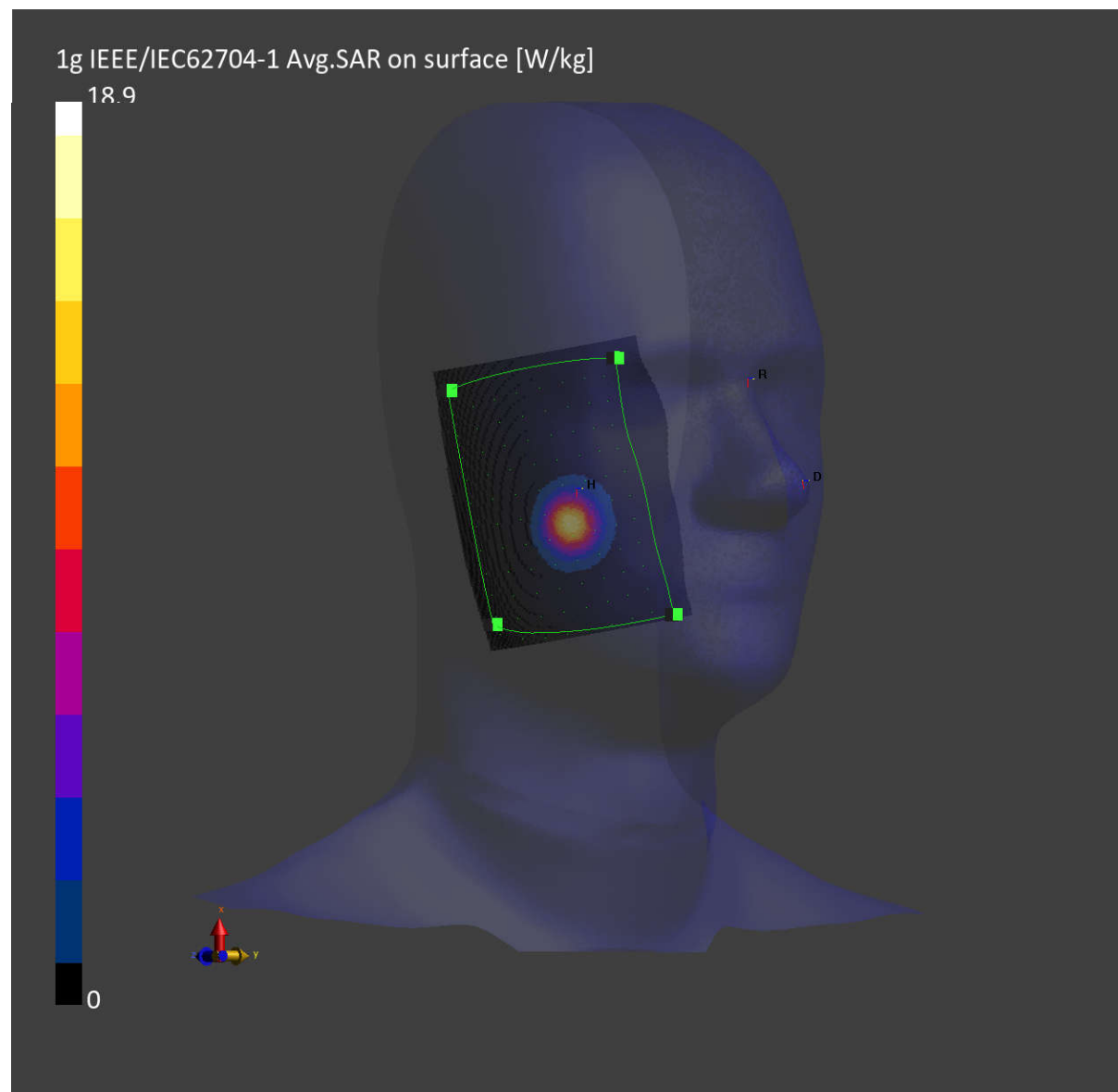
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	110.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	15.8	18.9
psSAR10g [W/Kg]	4.36	5.26
Power Drift [dB]	-0.25	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		67.4
Dist 3dB Peak [mm]		6.5

SAR Pattern



System Check_Head_5800MHz-H-Right

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

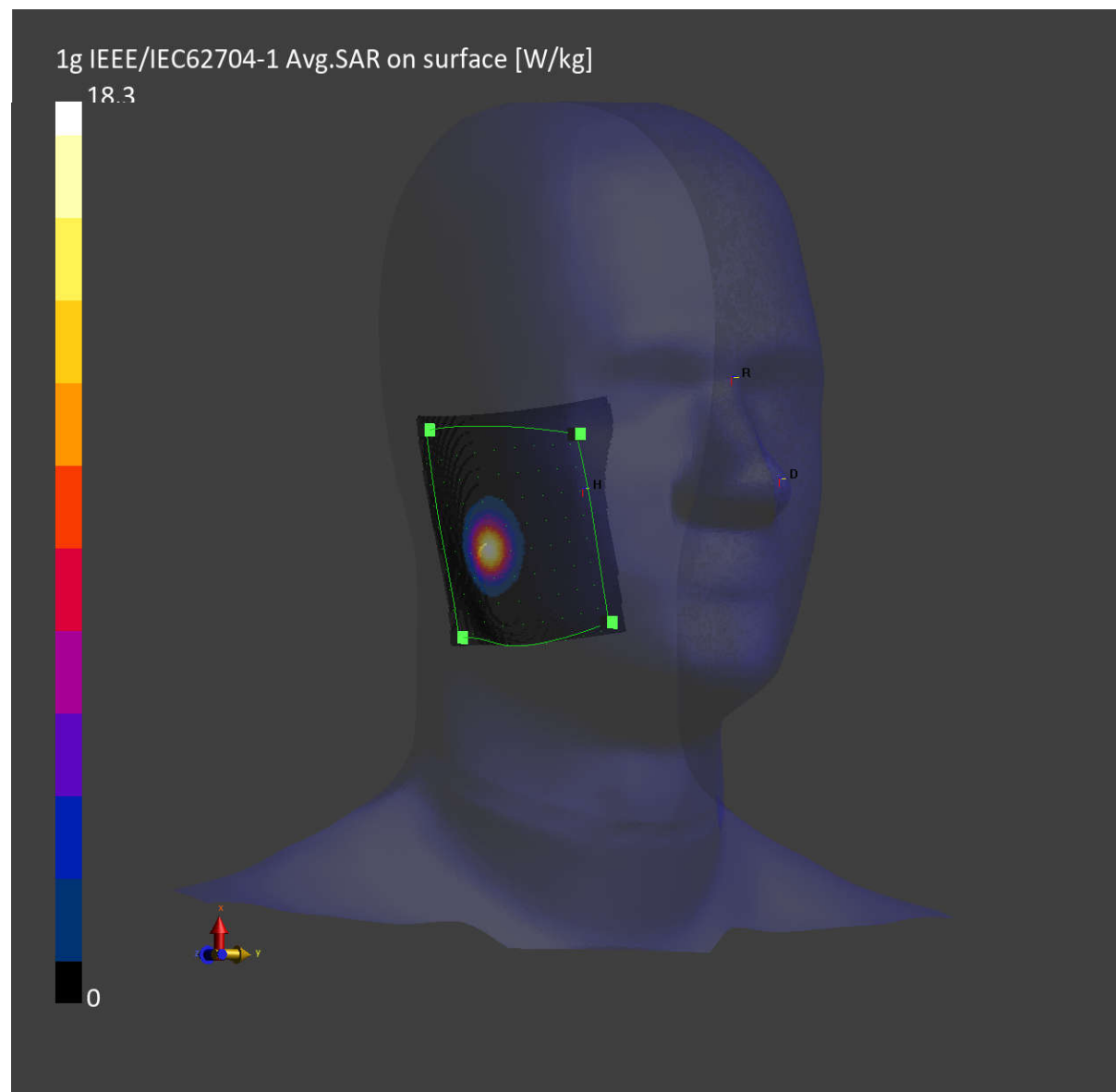
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	17.5	18.3
psSAR10g [W/Kg]	4.77	5.09
Power Drift [dB]	-0.12	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.8
Dist 3dB Peak [mm]		7.1

SAR Pattern



System Check_Head_5800MHz-C-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

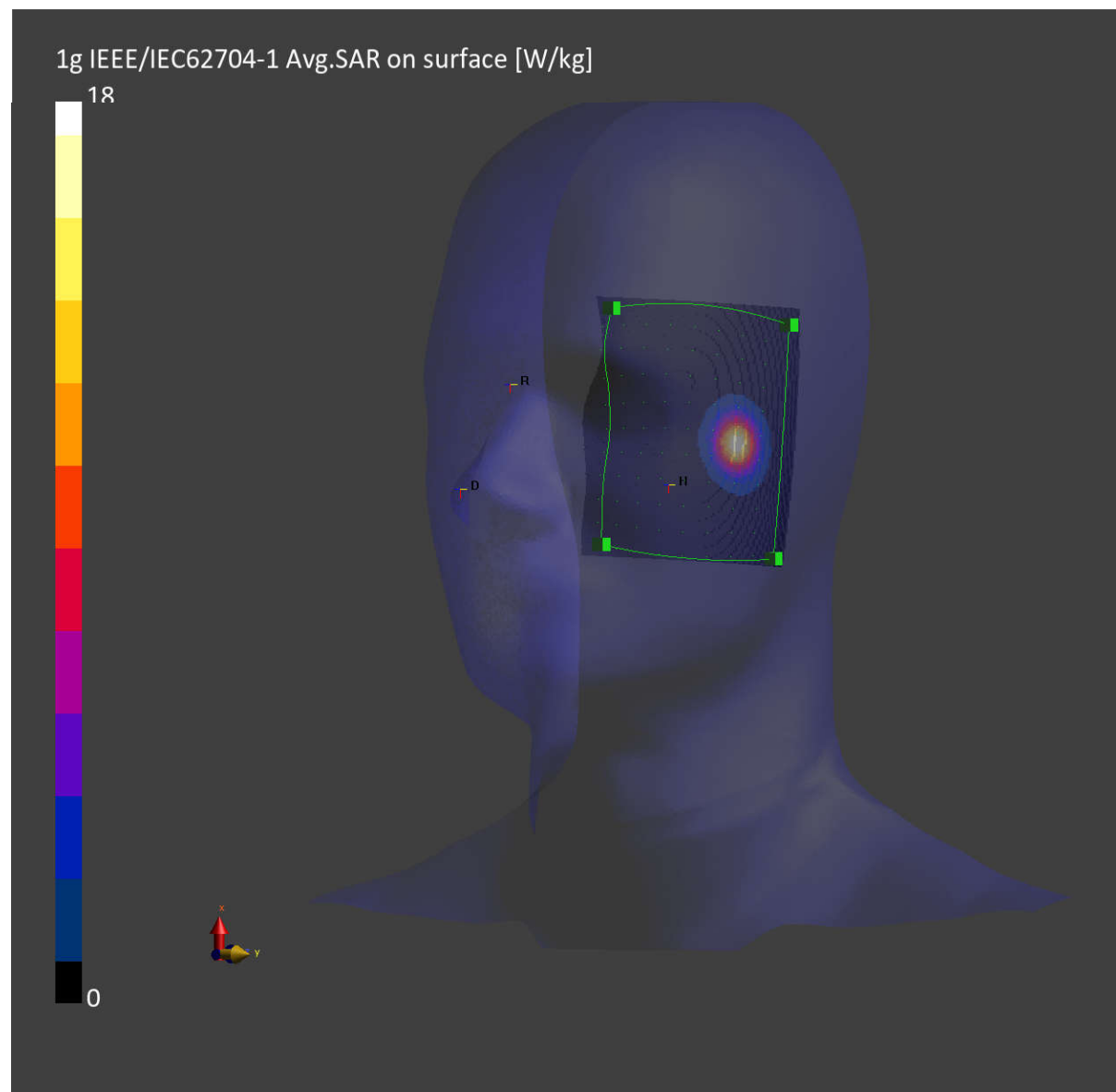
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	100.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	16.2	18.0
psSAR10g [W/Kg]	4.05	4.87
Power Drift [dB]	0.20	-0.20
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.2
Dist 3dB Peak [mm]		6.3

SAR Pattern



System Check_Head_5800MHz-F-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

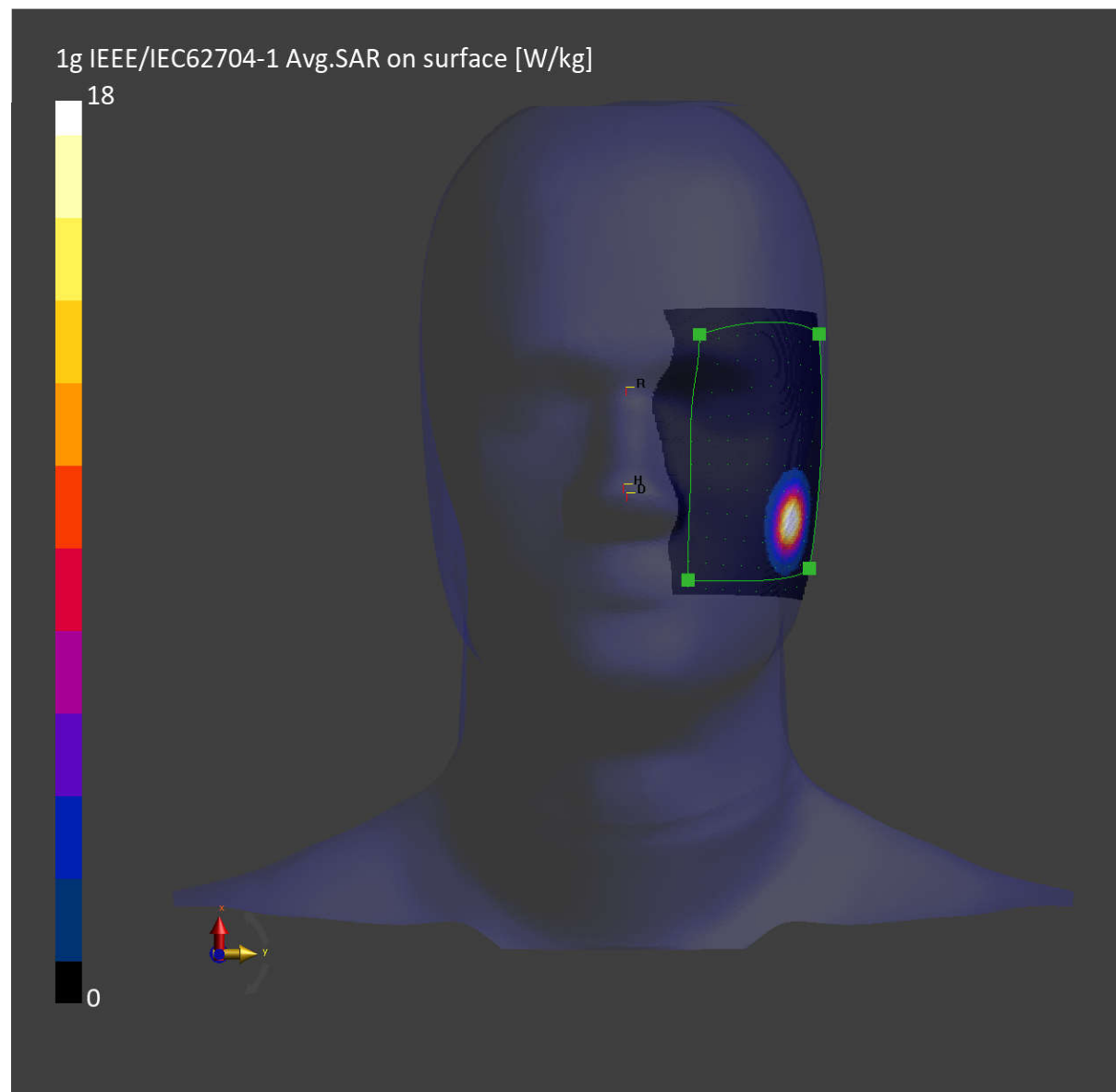
Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	110.0 x 85.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	18.3	18.0
psSAR10g [W/Kg]	4.68	4.83
Power Drift [dB]	0.14	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		67.6
Dist 3dB Peak [mm]		6.9

SAR Pattern



System Check_Head_5800MHz-H-Left

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Other

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Facedown, Head Simulating Liquid	DEFAULT, 0.00	D5GHz	CW, 0--	5800.000, 80	5.55	5.27	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
SAM Face-Down V10.0 -1050	HSL_5000_250617	EX3DV4 - SN7630, 2024-08-22	DAE4 Sn1650, 2024-11-25

Scans Setup

	FastVolume Scan	Zoom Scan
Grid Extents [mm]	120.0 x 95.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	5.0 x 5.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	3.0
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS	VMS
Scan Method	Measured	Measured

Measurement Results

	FastVolume Scan	Zoom Scan
Date	2025-06-17	2025-06-17
psSAR1g [W/Kg]	19.0	17.5
psSAR10g [W/Kg]	4.77	4.78
Power Drift [dB]	-0.00	0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.9
Dist 3dB Peak [mm]		6.7

SAR Pattern

